## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination CHEN ET AL. | Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,815,026	09-1998	Santin et al.	327/536
	В	US-5,181,091	01-1993	Harrington et al.	257/355
	С	US-5,798,560	08-1998	Ohkawa et al.	257/555
	D	US-5,432,368	07-1995	Jimenez, Jean	257/355
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	ł	US-			
	J	US-			
	κ	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 06104459 A	04-1994	Japan	YAGI et al.	H01L 29/91
	0					
	Р					
	Q					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	٦							
	>							
	>							
	x							

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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